

ALACARTE™ RELIABILITY SYMPOSIUM

**We will be holding our 2008 Reliability Symposium
the week of *April 7-11***

and we are putting on the following seminars:

Design for Reliability (DfR)

Date: April 7-8 (2 days)

Abstract: Learn the building block tools for reliability during the concept and design phase and learn how to integrate with the rest of your reliability program.

Best Accelerated Reliability Test Methods: HALT, ALT, and RDT

Date: April 9-10 (2 days)

Abstract: Highly Accelerated Life Testing (HALT), Accelerated Life Testing (ALT), and Reliability Demonstration Testing (RDT) are the best reliability testing techniques. This seminar will explain each and identify when to use which technique.

Climatic Testing Fundamentals

Date: April 7-8 (2 days)

Abstract: Review of the different types of climatic tests and when and how to apply them. Tests include temperature, temperature shock, humidity, altitude, rain, solar, salt/fog, ice, dust/sand, and more.

Design for Testability (DfT)

Date: April 9 (1 day)

Abstract: Learn about Stress-strength and failure of materials and electronics, variation and reliability, Design analysis and more.

Design of Experiments (DoE)

Date: April 7-8 (2 days)

Abstract: Learn the basic statistics behind a DOE as well as go through a hands-on workshop in which we perform a DOE on a specific product.

Design for Warranty Cost Reduction (DfW)

Date: April 10 (1 day)

Abstract: Introduces a proven warranty even cost model that helps identify warranty cost reduction solutions and feed back into design process for cost savings.

Mechanical Design for Reliability (MDfR)

Date: April 9 (1 day)

Abstract: Learn about FEA, Tolerance/Worst Case Analysis, Probabilistic Design Systems, and Fatigue and Fracture.

Root Cause Analysis (RCA)

Date: April 10-11 (2 day)

Abstract: Looks at RCA from a system and component level, identifying best tools, 5 Whys approach, 8 Step process, and FRACAS.

Software Reliability

Date: April 11 (1 day)

Abstract: Highlights best practices in Software Reliability and explains their application and positive impact to each of the development life cycle phases: Concept, Design, Implementation, and Testing.

Statistical Process Control (SPC)

Date: April 11 (1 day)

Abstract: This Statistical Process Control (SPC) course presents a number of valuable tools to assist you in evaluating process variation and to make sound decisions based on your data.

Location: 990 Richard Ave, Suite 101, Santa Clara, CA 95050

Price: \$1195 for each 2 day course, \$695 for each 1 day course, 25% discount for seminars taken via web-conference

Group Discounts: Every 5th registrant (or the 5th day for a single registrant) is free

Inquire if interested at education@opsalacarte.com or call (408) 472-3889.

www.opsalacarte.com/Pages/education/edu_intro.htm